

Form 1449 (Modified)

Information Disclosure

Statement By Applicant

(Use Several Sheets if Necessary)

Atty Docket No.

SNTCP001X2C1

Applicant:

Lescot, et al. Filing Date

July 12, 2001

Application No.:

To Be Assigned

Group

To Be Assigned

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub- class	Filing Date
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24	A2	6,103,561	08/15/00	Seshadri, et al.			03/19/99

Foreign Patent or Published Foreign Patent Application

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Examiner		Document	Publication	Country or		Sub-	Trans	lation
Initial	No.	No.	Date	Patent Office	Class	class	Yes	No
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\mathcal{O}	B2	Nishath K. Verghese et al., "Fast Parasitic Extraction for Substrate Coupling in			
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1 1		Simulation and Power Distribution Synthesis, IEEE Journal of Solid-State			
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	D2	Francois J.R. Clement, IC SUBSTRATE NOISE MODELING WITH IMPROVED SURFACE GRIDDING TECHNIQUE, U.S. Patent Application No. 09/495,078, filed January 31, 2000, 57 pages.		
	D3	Francois J.R. Clement, IC SUBSTRATE NOISE MODELING, U.S. Patent Application No. 09/262,735, filed March 4, 1999, 54 pages.		
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